



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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企业微信二维码



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Product Summary

BV_{DSS}	$R_{DS(ON) Max}$	I_D $T_A = +25^\circ C$
-20V	38m Ω @ $V_{GS} = -4.5V$	-5.5A
	52m Ω @ $V_{GS} = -2.5V$	-5.0A

Features and Benefits

- Low Input Capacitance
- Low On-Resistance
- Fast Switching Speed

Description and Applications

This MOSFET is designed to meet the stringent requirements of automotive applications. It is qualified to AEC-Q101, supported by a PPAP, and ideal for use in:

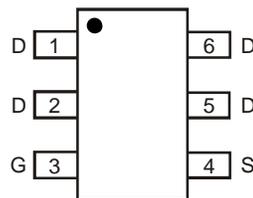
- DC-DC converters
- Motor controls
- Power management functions
- Analog switches

Mechanical Data

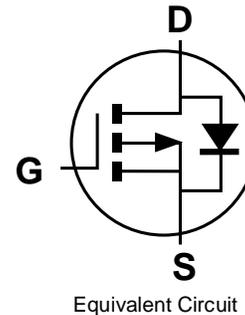
- Package: TSOT26
- Package Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish - Matte Tin Annealed over Copper Leadframe; Solderable per MIL-STD-202, Method 208 e3
- Weight: 0.013 grams (Approximate)



Top View



Top View
Pinout



Maximum Ratings (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	-20	V
Gate-Source Voltage			V_{GSS}	± 12	V
Continuous Drain Current (Note 6) $V_{GS} = -4.5\text{V}$	Steady State	$T_A = +25^\circ\text{C}$	I_D	-5.5	A
		$T_A = +70^\circ\text{C}$		-4.5	
Continuous Drain Current (Note 7) $V_{GS} = -4.5\text{V}$	Steady State	$T_C = +25^\circ\text{C}$	I_D	-13	A
		$T_C = +70^\circ\text{C}$		-10	
Pulsed Drain Current (10 μs Pulse, Duty Cycle = 1%)			I_{DM}	-40	A
Continuous Source-Drain Diode Current (Note 6)			I_S	-2.2	A
Avalanche Current (Note 8) $L = 0.1\text{mH}$			I_{AS}	-16	A
Avalanche Energy (Note 8) $L = 0.1\text{mH}$			E_{AS}	13.5	mJ

Thermal Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic		Symbol	Value	Unit
Total Power Dissipation (Note 5)	$T_A = +25^\circ\text{C}$	P_D	1.2	W
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	$R_{\theta JA}$	105	$^\circ\text{C/W}$
Total Power Dissipation (Note 6)	$T_A = +25^\circ\text{C}$	P_D	1.5	W
Thermal Resistance, Junction to Ambient (Note 6)	Steady State	$R_{\theta JA}$	80	$^\circ\text{C/W}$
Thermal Resistance, Junction to Case (Note 7)	Steady State	$R_{\theta JC}$	16	$^\circ\text{C/W}$
Operating and Storage Temperature Range		T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

Electrical Characteristics (@ $T_A = +25^\circ\text{C}$, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 9)						
Drain-Source Breakdown Voltage	BV_{DSS}	-20	—	—	V	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$
Zero Gate Voltage Drain Current	I_{DSS}	—	—	-1	μA	$V_{DS} = -16\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	—	—	± 100	nA	$V_{GS} = \pm 12\text{V}, V_{DS} = 0\text{V}$
ON CHARACTERISTICS (Note 9)						
Gate Threshold Voltage	$V_{GS(TH)}$	-0.6	—	-1.5	V	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	27	38	m Ω	$V_{GS} = -4.5\text{V}, I_D = -8.9\text{A}$
		—	38	52		$V_{GS} = -2.5\text{V}, I_D = -6.9\text{A}$
Diode Forward Voltage	V_{SD}	—	-0.7	-1.2	V	$V_{GS} = 0\text{V}, I_S = -2.9\text{A}$
DYNAMIC CHARACTERISTICS (Note 10)						
Input Capacitance	C_{iss}	—	834	—	pF	$V_{DS} = -10\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	—	133	—		
Reverse Transfer Capacitance	C_{rss}	—	105	—		
Gate Resistance	R_G	—	4.9	—	Ω	$V_{DS} = 0\text{V}, V_{GS} = 0\text{V}, f = 1.0\text{MHz}$
Total Gate Charge ($V_{GS} = -4.5\text{V}$)	Q_g	—	8.6	—	nC	$V_{DS} = -6\text{V}, I_D = -8.9\text{A}$
Total Gate Charge ($V_{GS} = -8\text{V}$)	Q_g	—	19	—		
Gate-Source Charge	Q_{gs}	—	1.5	—		
Gate-Drain Charge	Q_{gd}	—	2.5	—		
Turn-On Delay Time	$t_{D(ON)}$	—	5.8	—	ns	$V_{DD} = -6\text{V}, R_L = 6\Omega, V_{GS} = -4.5\text{V}, R_G = 6\Omega, I_D = -1\text{A}$
Turn-On Rise Time	t_R	—	7.7	—		
Turn-Off Delay Time	$t_{D(OFF)}$	—	28.1	—		
Turn-Off Fall Time	t_F	—	14.6	—		
Body Diode Reverse Recovery Time	t_{RR}	—	9.8	—	ns	$I_F = -8.9\text{A}, di/dt = -100\text{A}/\mu\text{s}$
Body Diode Reverse Recovery Charge	Q_{RR}	—	2.7	—	nC	$I_F = -8.9\text{A}, di/dt = -100\text{A}/\mu\text{s}$

- Notes:
- Device mounted on FR-4 PC board, with minimum recommended pad layout, single sided.
 - Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.
 - Thermal resistance from junction to soldering point (on the exposed drain pad).
 - I_{AS} and E_{AS} ratings are based on low frequency and duty cycles to keep $T_J = +25^\circ\text{C}$.
 - Short duration pulse test used to minimize self-heating effect.
 - Guaranteed by design. Not subject to product testing.

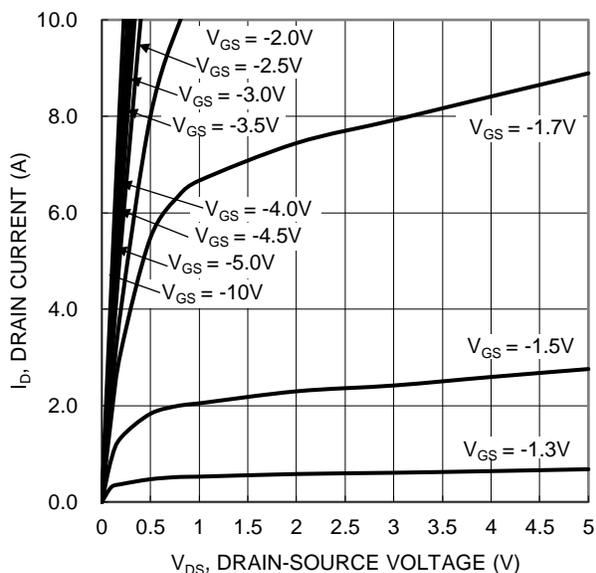


Figure 1. Typical Output Characteristic

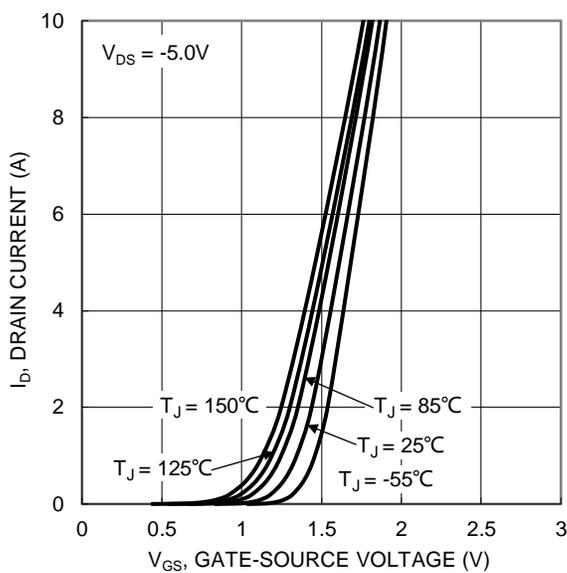


Figure 2. Typical Transfer Characteristic

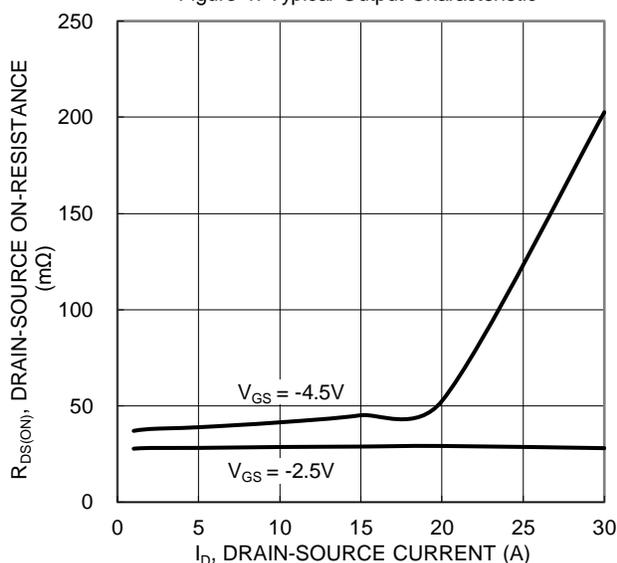


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

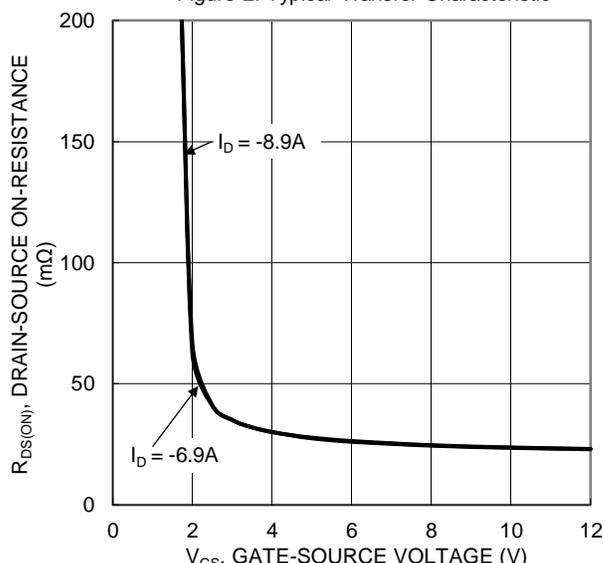


Figure 4. Typical Transfer Characteristic

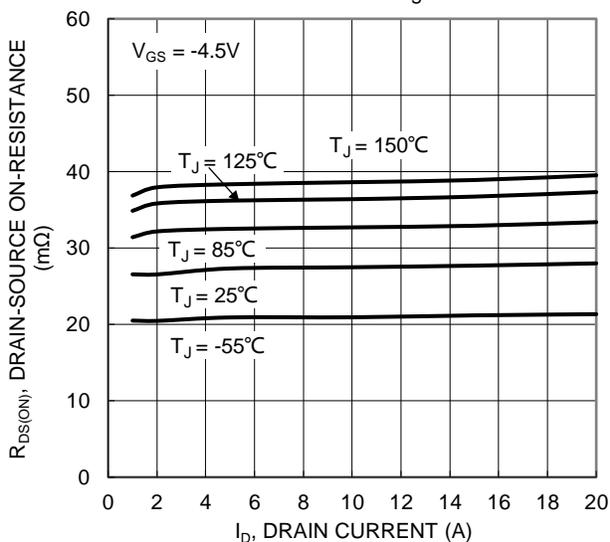


Figure 5. Typical On-Resistance vs. Drain Current and Temperature

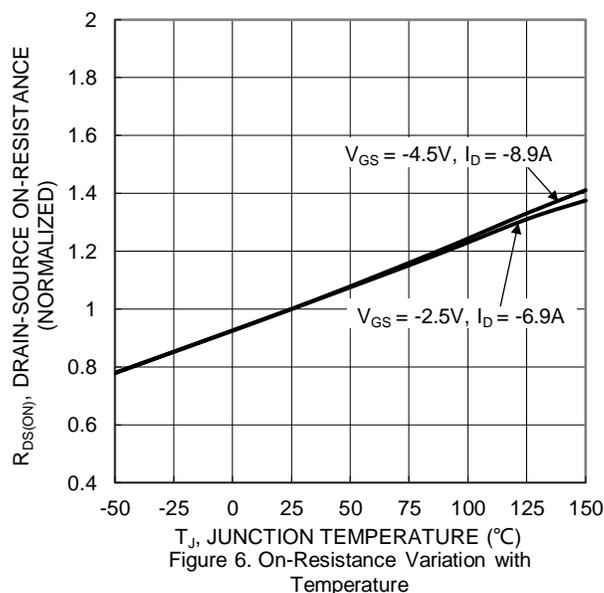


Figure 6. On-Resistance Variation with Temperature

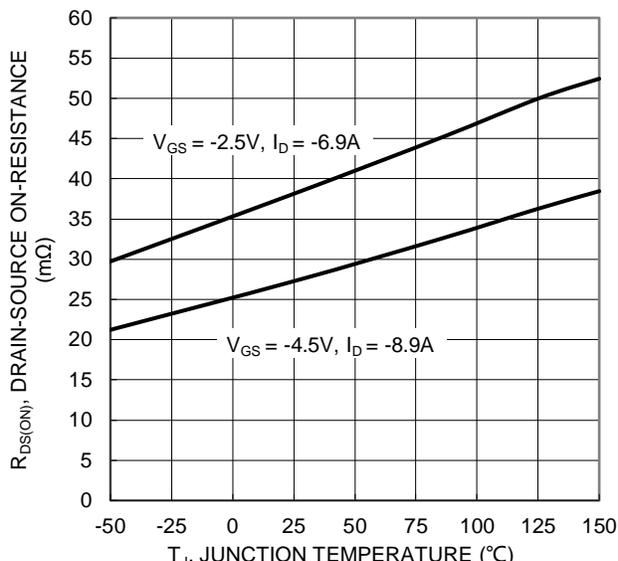


Figure 7. On-Resistance Variation with Temperature

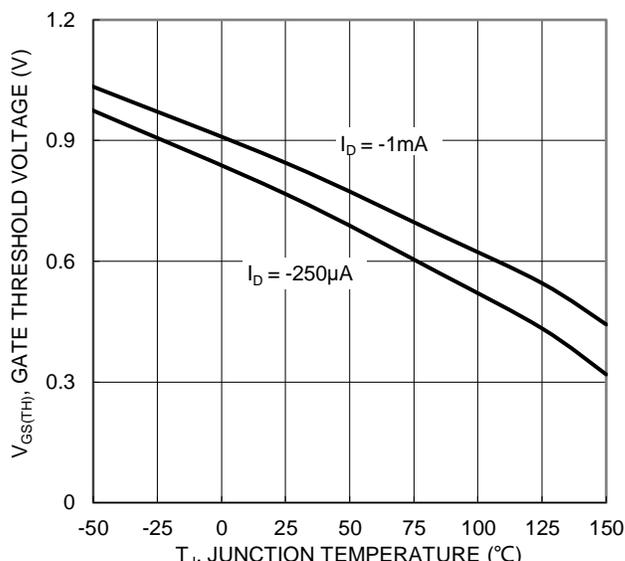


Figure 8. Gate Threshold Variation vs. Junction Temperature

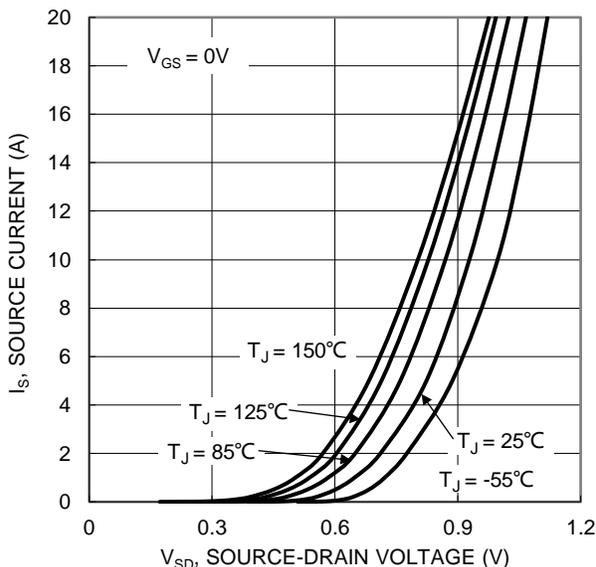


Figure 9. Diode Forward Voltage vs. Current

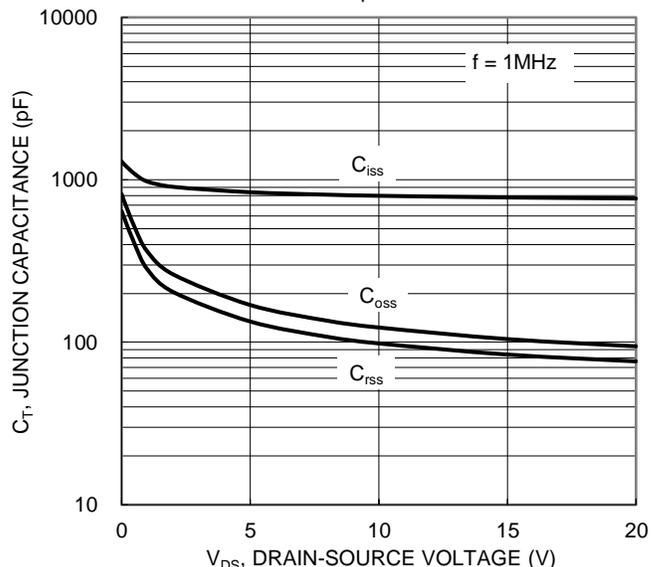


Figure 10. Typical Junction Capacitance

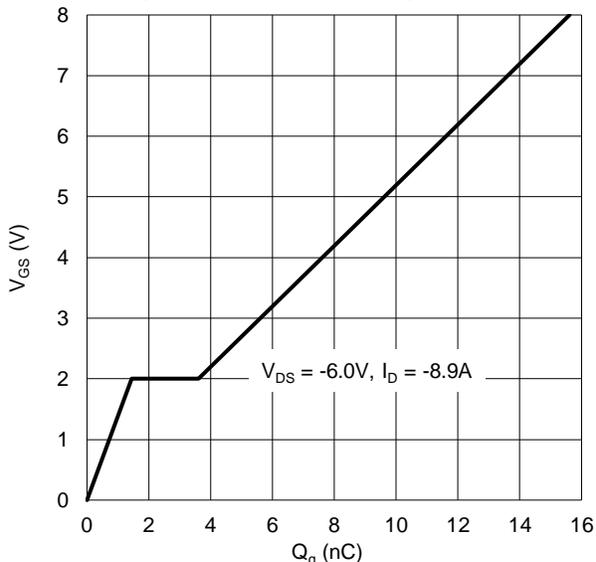


Figure 11. Gate Charge

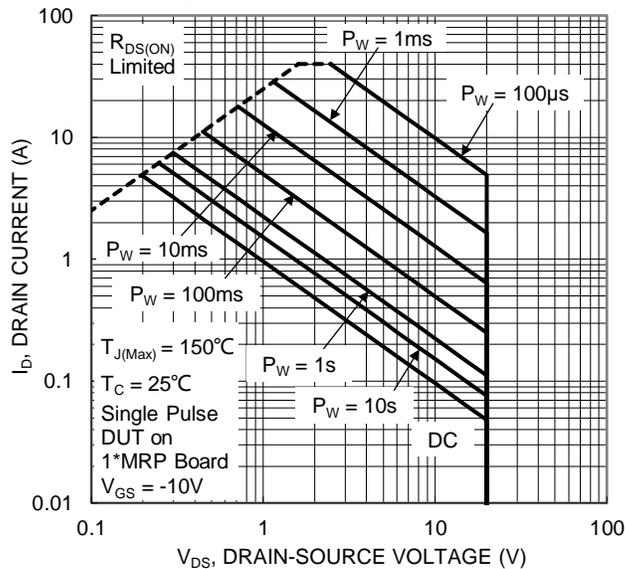


Figure 12. SOA, Safe Operation Area

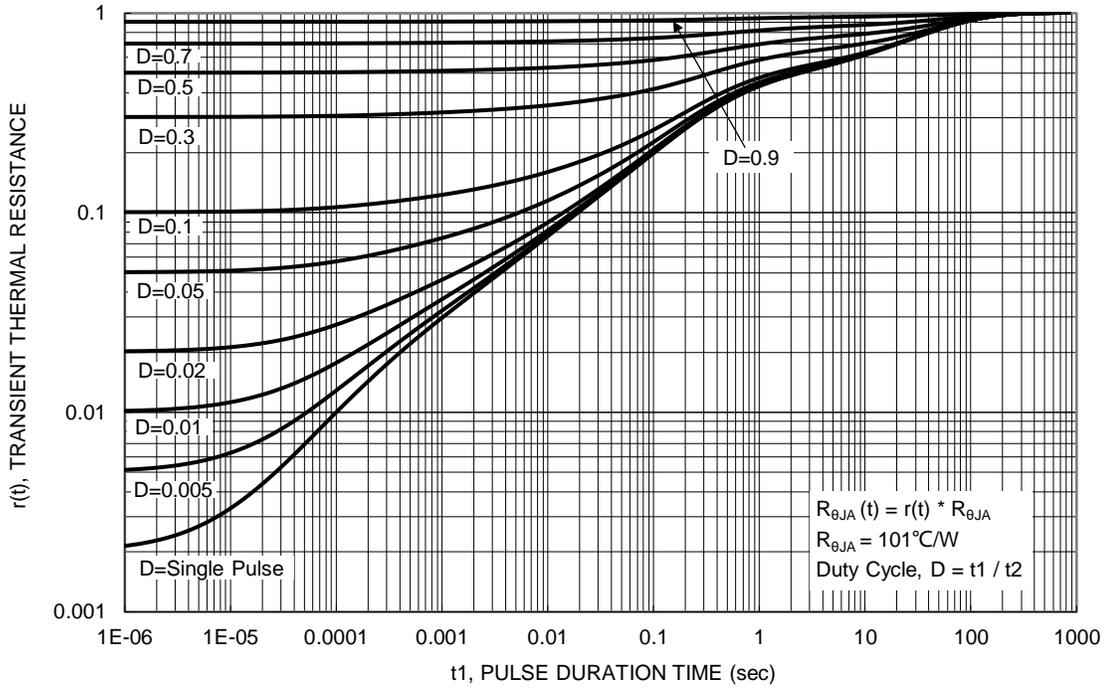
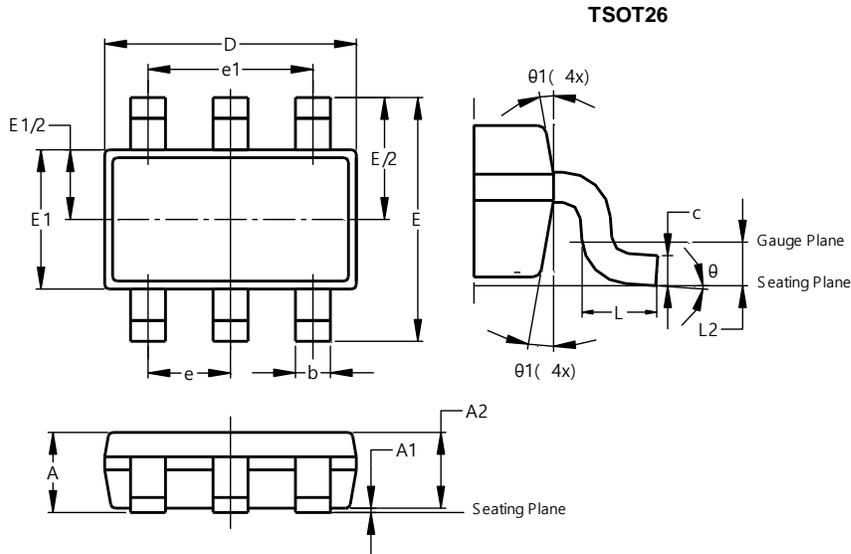


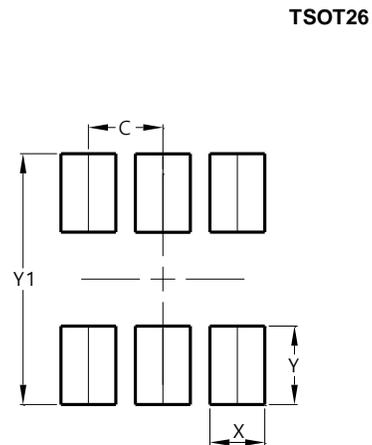
Figure 13. Transient Thermal Resistance

Package Outline Dimensions



TSOT26			
Dim	Min	Max	Typ
A	–	1.00	–
A1	0.010	0.100	–
A2	0.840	0.900	–
D	2.800	3.000	2.900
E	2.800 BSC		
E1	1.500	1.700	1.600
b	0.300	0.450	–
c	0.120	0.200	–
e	0.950 BSC		
e1	1.900 BSC		
L	0.30	0.50	–
L2	0.250 BSC		
θ	0°	8°	4°
$\theta 1$	4°	12°	–
All Dimensions in mm			

Suggested Pad Layout



Dimensions	Value (in mm)
C	0.950
X	0.700
Y	1.000
Y1	3.200